

# A direct observation of ultrafast energy transfer, charge trapping and thermal quenching in luminescent materials

David Van der Heggen<sup>1,#</sup>, Korneel Molken<sup>2</sup>, Jonas J. Joos<sup>1</sup>, Daniel Rytz<sup>3</sup>,  
Lucas C. V. Rodrigues<sup>4</sup>, Pieter Geiregat<sup>2</sup>, Philippe F. Smet<sup>1</sup>

<sup>1</sup> LumiLab, Dept. of Solid State Science, Ghent University, Krijgslaan 285, 9000 Gent, Belgium

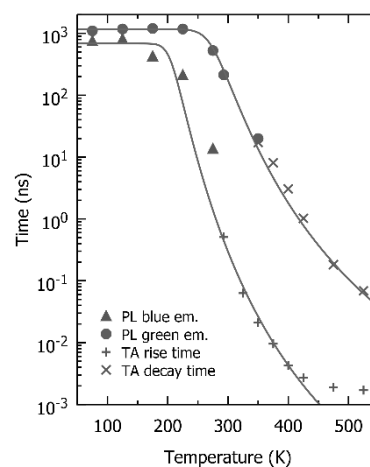
<sup>2</sup> PCN, Dept. of Chemistry, Ghent University, Krijgslaan 289, 9000 Gent, Belgium

<sup>3</sup> BREVALOR Sàrl, Impasse des Frênes 1, CH-1669 Les Sciernes, Switzerland

<sup>4</sup> Department of Fundamental Chemistry, Institute of Chemistry, 10 University of Sao Paulo, Sao Paulo-SP, 05508-000, Brazil

Persistent phosphors, materials that glow for hours after excitation has ended, are often seen as a typical example of slow-emitting materials. Yet, their performance hinges on ultrafast processes like energy and charge transfer.[1] Here we will present new insights into the excited-state dynamics of the benchmark persistent phosphor SrAl<sub>2</sub>O<sub>4</sub>:Eu,Dy (SAO:Eu,Dy).[2] Using a novel combination of transient absorption and time-resolved luminescence spectroscopy, we've captured the full dynamic range of these processes, spanning from picosecond to microsecond timescales.

Our findings reveal that nonradiative energy transfer between distinct Eu<sup>2+</sup> centers occurs within nanoseconds, accelerating with increasing temperature to reach a remarkable 5-picosecond limit at high temperatures. Charge transfer from Eu<sup>2+</sup> to trapping defects is ten times faster than radiative decay, while reverse transfer - triggered by optical stimulation - happens in just 2–3 picoseconds. This work demonstrates that pump-probe techniques can resolve the ultrafast events governing seemingly slow phosphors, bridging the gap between fast and slow timescales.



[1] Romero M. et al. (2025) Adv. Opt. Mater., 13, e01847

[2] Van der Heggen D. et al. (2022) Adv. Fun. Mater., 32, 2208809

# corresponding author: David.VanderHeggen@UGent.be